



YOUSHANG SEMICONDUCTOR

设计研发新型功率器件

各类小信号开关

中低压及高压大电流等场效应管

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Product Summary

BV _{DSS}	R _{DS(ON)} Max	I _D Max T _C = +25°C
80V	2.9mΩ @ V _{GS} = 10V	165A
	5.3mΩ @ V _{GS} = 6V	133A

Features

- 100% Unclamped Inductive Switching (UIS) Test in Production – Ensures More Reliable and Robust End Application
- High Conversion Efficiency
- Low R_{DS(ON)} – Minimizes On-State Losses
- Low Input Capacitance
- Fast Switching Speed
- **Lead-Free Finish; RoHS Compliant (Notes 1 & 2)**
- **Halogen and Antimony Free. “Green” Device (Note 3)**

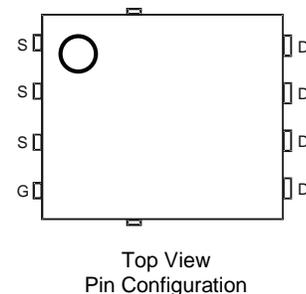
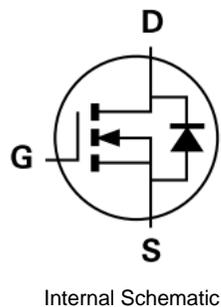
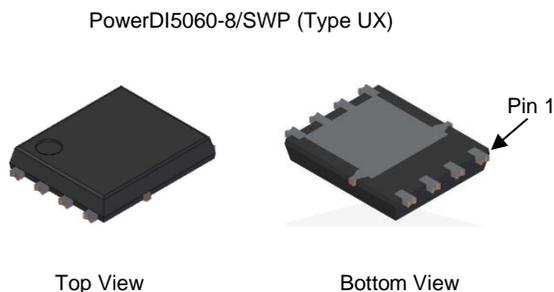
Description and Applications

This new generation N-Channel Enhancement Mode MOSFET is designed to minimize R_{DS(ON)} yet maintain superior switching performance. This device is ideal for use in power management and load switches.

- Engine-management systems
- Body control electronics
- DC-DC converters

Mechanical Data

- Package: PowerDI[®]5060-8
- Package Material: Molded Plastic, “Green” Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Terminals: Finish – Matte Tin Annealed over Copper Leadframe. Solderable per MIL-STD-202, Method 208 
- Weight: 0.097 grams (Approximate)



Maximum Ratings (@T_C = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	80	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current, V _{GS} = 10V (Note 5)	I _D	T _C = +25°C	165
		T _C = +100°C	117
Maximum Continuous Body Diode Forward Current (Note 5)	I _S	165	A
Pulsed Drain Current (10μs Pulse, Duty Cycle = 1%)	I _{DM}	660	A
Pulsed Body Diode Forward Current (10μs Pulse, Duty Cycle = 1%)	I _{SM}	660	A
Avalanche Current, L = 3mH	I _{AS}	28.6	A
Avalanche Energy, L = 3mH	E _{AS}	1227	mJ

Thermal Characteristics (@T_C = +25°C, unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 6)	P _D	T _A = +25°C	4.1
Thermal Resistance, Junction to Ambient (Note 6)		R _{θJA}	37
Total Power Dissipation (Note 5)	P _D	T _C = +25°C	150
Thermal Resistance, Junction to Case (Note 5)		R _{θJC}	1
Operating and Storage Temperature Range	T _J , T _{STG}	-55 to +175	°C

- Notes:
- Thermal resistance from junction to soldering point (on the exposed drain pad).
 - Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate.

Electrical Characteristics (@T_C = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 7)						
Drain-Source Breakdown Voltage	BV _{DSS}	80	—	—	V	V _{GS} = 0V, I _D = 1mA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	1	μA	V _{DS} = 64V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 7)						
Gate Threshold Voltage	V _{GS(TH)}	2	—	4	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	2.1	2.9	mΩ	V _{GS} = 10V, I _D = 30A
		—	3.5	5.3	mΩ	V _{GS} = 6V, I _D = 20A
Diode Forward Voltage	V _{SD}	—	0.8	1.2	V	V _{GS} = 0V, I _S = 20A
DYNAMIC CHARACTERISTICS (Note 8)						
Input Capacitance	C _{iss}	—	5466	—	pF	V _{DS} = 40V, V _{GS} = 0V f = 1MHz
Output Capacitance	C _{oss}	—	1911	—		
Reverse Transfer Capacitance	C _{rss}	—	124	—		
Gate Resistance	R _g	—	1.2	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge	Q _g	—	87	—	nC	V _{DS} = 40V, I _D = 30A V _{GS} = 10V
Gate-Source Charge	Q _{gs}	—	27	—		
Gate-Drain Charge	Q _{gd}	—	24	—		
Turn-On Delay Time	t _{D(ON)}	—	15	—	ns	V _{DD} = 40V, V _{GS} = 10V I _D = 30A, R _g = 3Ω
Turn-On Rise Time	t _r	—	50	—		
Turn-Off Delay Time	t _{D(OFF)}	—	57	—		
Turn-Off Fall Time	t _f	—	43	—		
Body Diode Reverse-Recovery Time	t _{RR}	—	72	—	ns	I _F = 30A, di/dt = 100A/μs
Body Diode Reverse-Recovery Charge	Q _{RR}	—	157	—	nC	

Notes: 7. Short duration pulse test used to minimize self-heating effect.
 8. Guaranteed by design. Not subject to product testing.

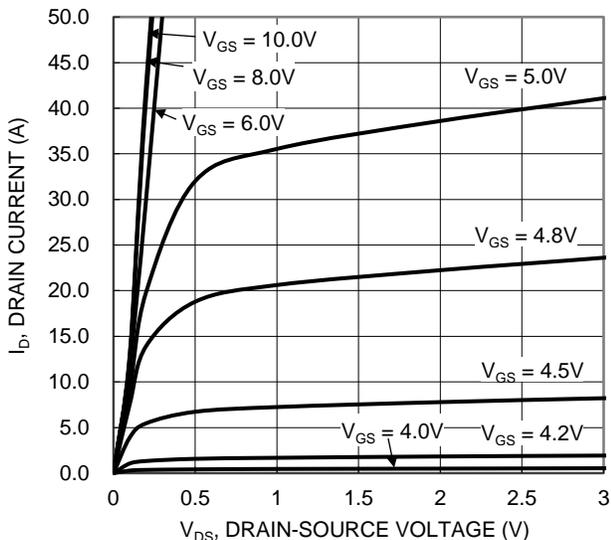


Figure 1. Typical Output Characteristic

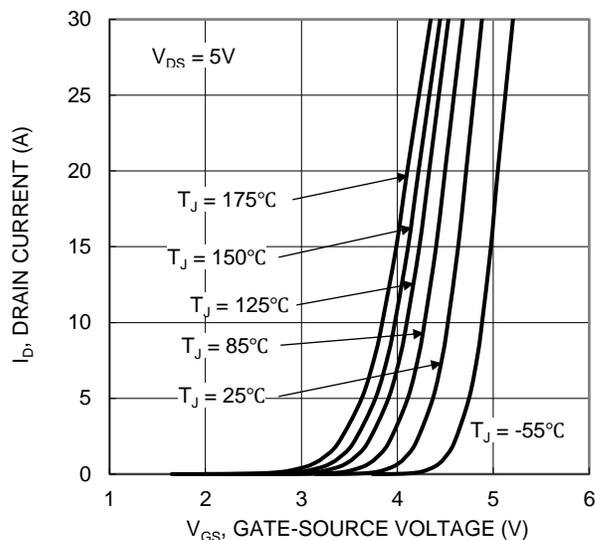


Figure 2. Typical Transfer Characteristic

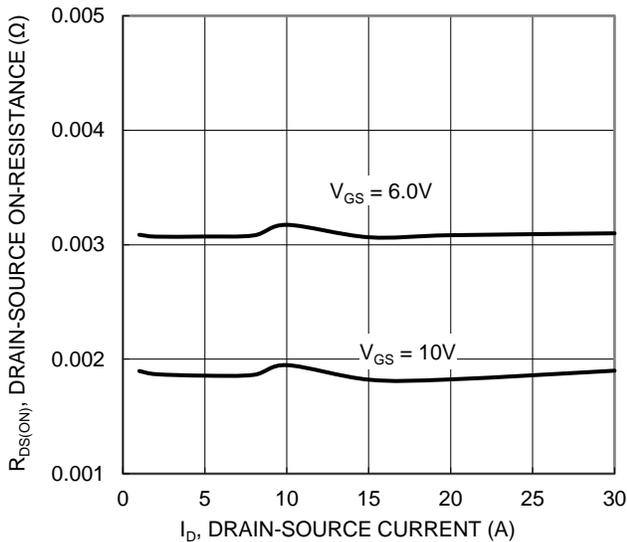


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

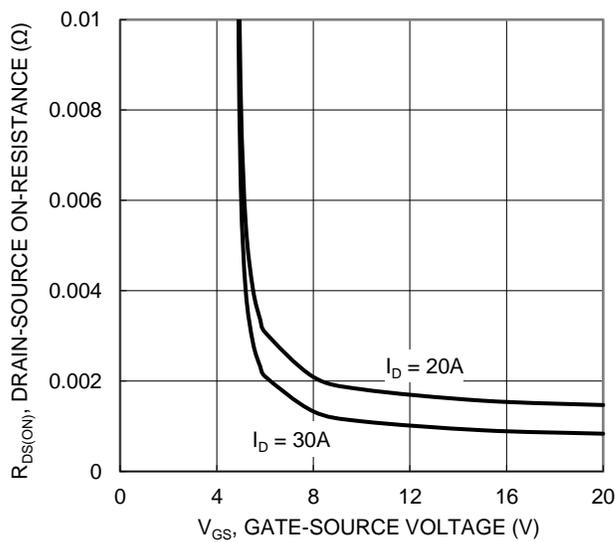


Figure 4. Typical Transfer Characteristic

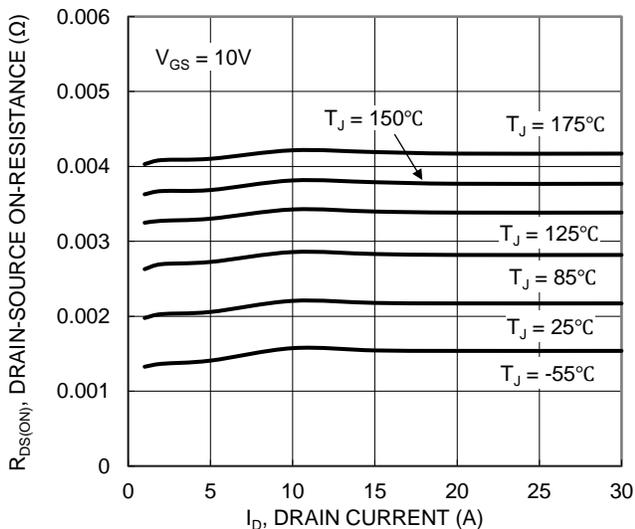


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

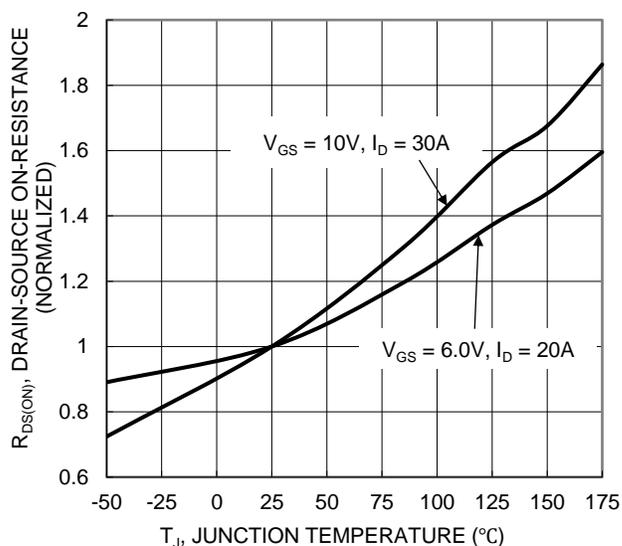


Figure 6. On-Resistance Variation with Junction Temperature

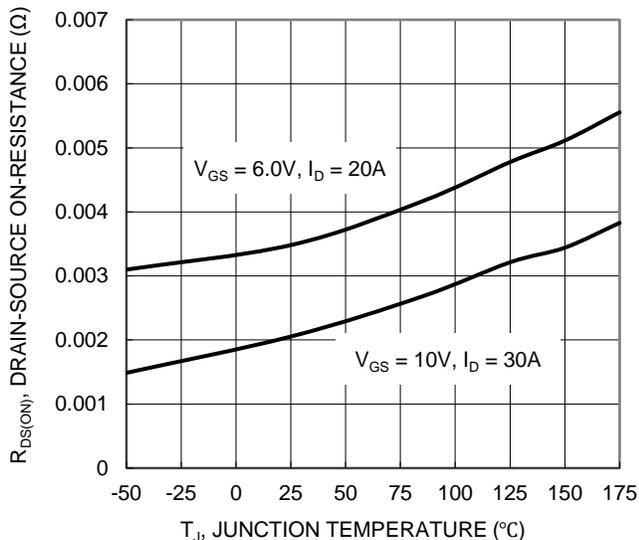


Figure 7. On-Resistance Variation with Junction Temperature

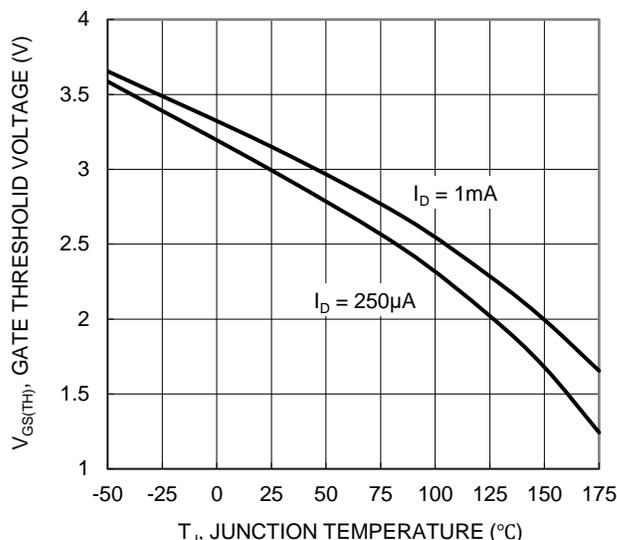


Figure 8. Gate Threshold Variation vs. Junction Temperature

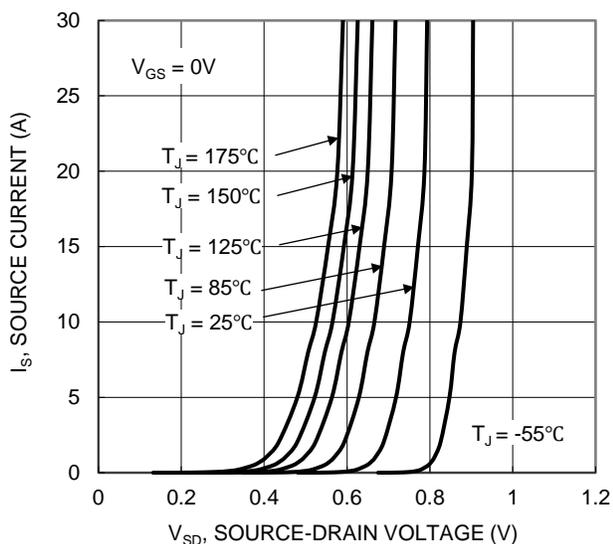


Figure 9. Diode Forward Voltage vs. Current

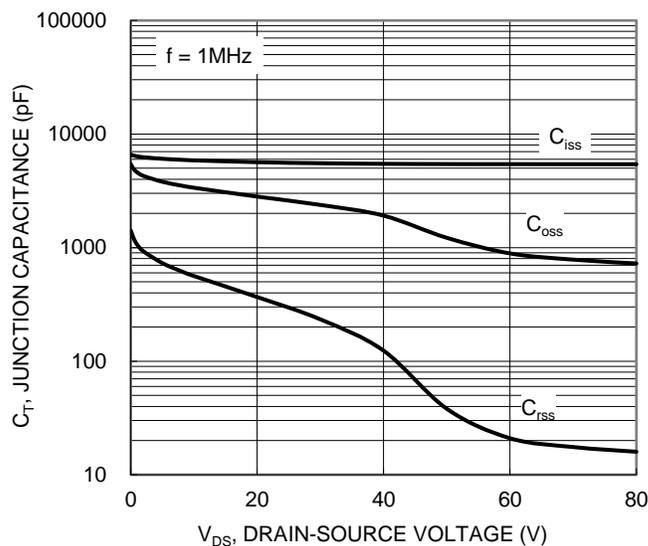


Figure 10. Typical Junction Capacitance

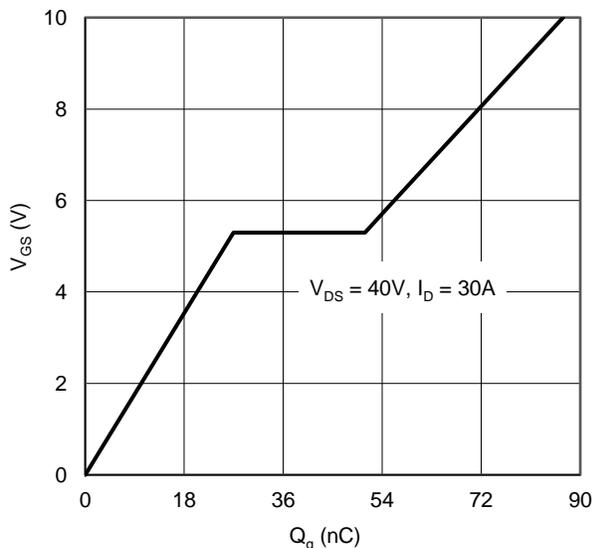


Figure 11. Gate Charge

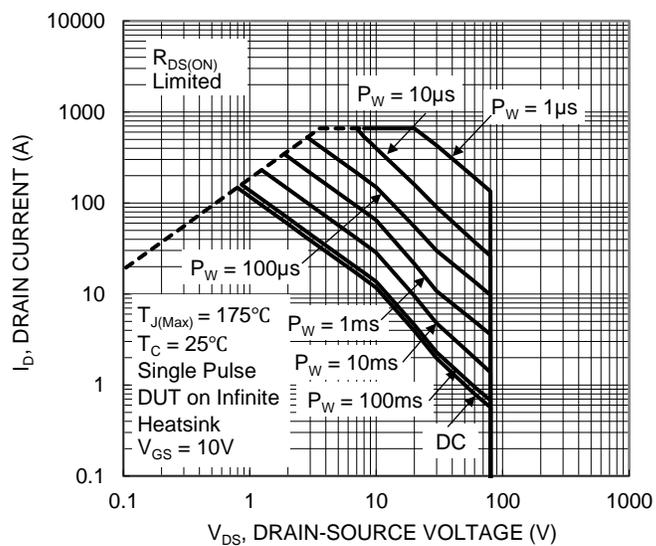


Figure 12. SOA, Safe Operation Area

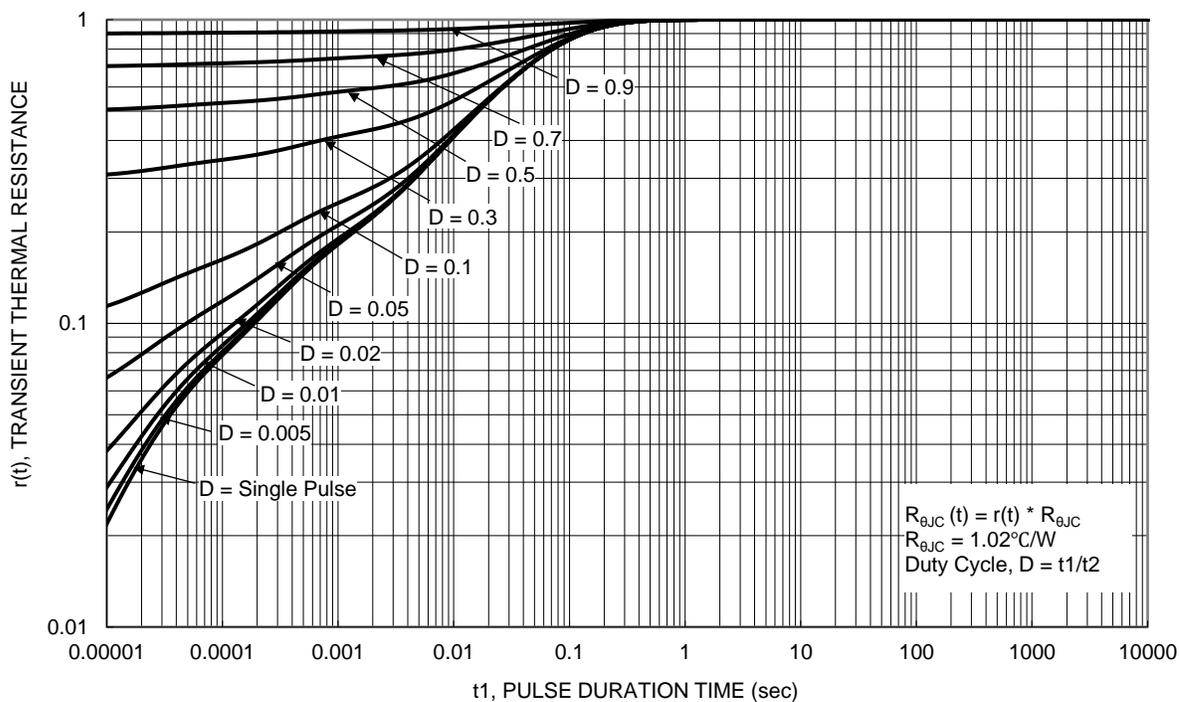


Figure 13. Transient Thermal Resistance

